

Non-Contact Sheet Resistance Tester

DATA SHEET - EddyCus[®] TF lab 4040 series

HIGHLIGHTS

- Contact-free & real-time
- Accurate single-point measurement of sheet resistance for conductive thin films (Ohm/sq)
- Layer thickness measurement of metal films (nm)
- Layer and substrate thickness monitoring (μm)
- Characterization of multilayer systems on request
- Manual mapping of sheet resistance guided by an easy-to-handle software

APPLICATIONS

- > Architectural glass (LowE)
- > Touch screens & flat monitors
- > OLED & LED applications
- > Smart-glass applications
- > Transparent antistatic foils
- > Photovoltaics
- > Semiconductors
- > De-icing & heating applications
- > Batteries & fuel cells
- > Packaging materials



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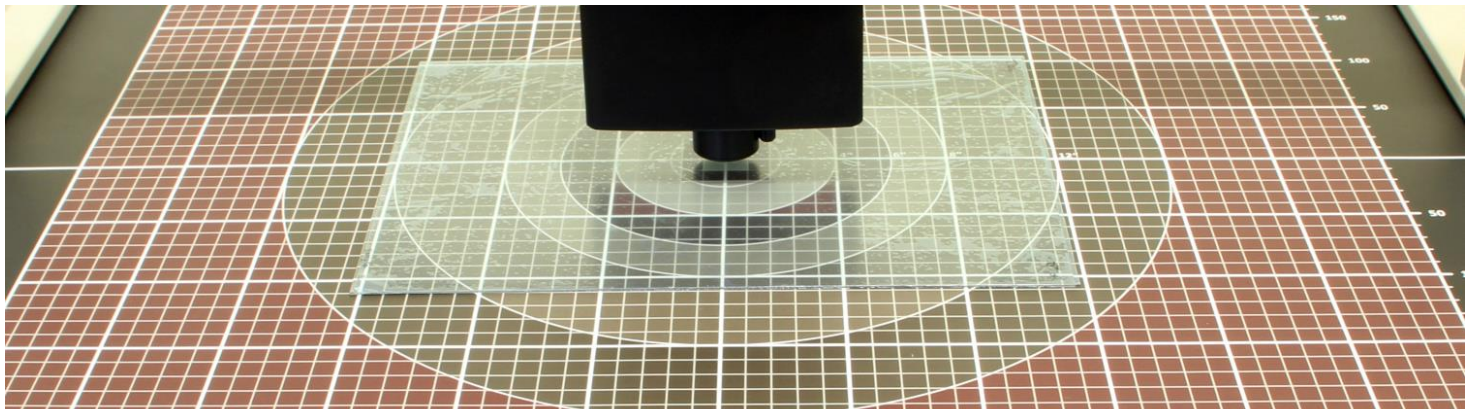
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DATA SHEET

EddyCus® TF lab 4040 series – Sheet Resistance Tester



EddyCus® TF lab 4040 series

Sheet resistance measurement technology

Non-contact eddy current sensor

Substrates

e.g. foil, glass and wafer

Substrate area

29.5 x 25.6 inch / 750 x 650 mm
(for measurement of 16 inch / 400 x 400 mm samples)

Max. sample thickness/sensor gap (defines distances)

1 / 2 / 5 / 10 / 25 mm (defined by the thickest sample/application)

Sheet resistance range

0.0001 – 10 Ohm/sq; 2 % accuracy & 1 % repeatability
10 – 100 Ohm/sq; 3 % accuracy & 1.5% repeatability
100 – 500 Ohm/sq; 4 % accuracy & 2% repeatability
100 – 1,000 Ohm/sq; 5 % accuracy & 2.5 % repeatability
1,000 – 3,000 Ohm/sq; 8 % accuracy & 4 % repeatability

Thickness measurement of thin films (e.g. copper)

2 nm – 2 mm (in accordance with sheet resistance)

Device dimension (w/h/d)

30 x 12 x 26 inch / 760 x 310 x 660 mm

Weight

20 kg

Available features

Metal thickness measurement
Sheet resistance anisotropy sensor
Optical transparency

SOFTWARE & HANDLING – EddyCus® TF lab Control